

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: Q76579

Ulrich WEGMANN, et al.

10628431

Appln. No.: Not Yet Assigned

Confirmation No.: Not Yet Assigned

Group Art Unit: Not Yet Assigned

Filed: July 29, 2003

Examiner: Not Yet Assigned

For:

METHOD AND APPARATUS FOR DETERMINING THE INFLUENCING OF THE

STATE OF POLARIZATION BY AN OPTICAL SYSTEM, AND AN ANALYSER

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §§ 1.97 and 1.98

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached PTO/SB/08 A & B (modified) form and/or listed herein and which the Examiner may deem material to patentability of the claims of the above-identified application.

One copy of each of the listed documents, excluding the U.S. patent documents, is submitted herewith.

The present Information Disclosure Statement is being filed: (1) No later than three months from the application's filing date for an application other than a continued prosecution application (CPA) under §1.53(d); (2) Before the mailing date of the first Office Action on the merits (whichever is later); or (3) Before the mailing date of the first Office Action after filing a

INFORMATION DISCLOSURE STATEMENT

U.S. Appln. No.: Not Yet Assigned

Attorney Docket No.: Q76579

request for continued examination (RCE) under §1.114, and therefore, no Statement under

37 C.F.R. § 1.97(e) or fee under 37 C.F.R. § 1.17(p) is required.

In compliance with the concise explanation requirement under 37 C.F.R. § 1.98(a)(3) for

foreign language documents, Applicant encloses herewith a copy of a German Office Action in a

counterpart application citing such documents, together with an English-language version (if not

already included) of that portion of the German Office Action indicating the degree of relevance

found by the foreign patent office. Additionally, Applicant refers the Examiner to the

Background discussion of the above-identified application, where certain of the foreign language

references are discussed further.

The submission of the listed documents is not intended as an admission that any such

document constitutes prior art against the claims of the present application. Applicant does not

waive any right to take any action that would be appropriate to antedate or otherwise remove any

listed document as a competent reference against the claims of the present application.

Respectfully submitted,

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WASHINGTON OFFICE

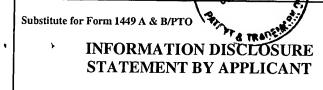
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Date: October 29, 2003

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| Filing Date | July 29, 2003 | | |
| First Named Inventor | Ulrich WEGMANN | | |
| Art Unit | Not Yet Assigned | | |
| Examiner Name | Not Yet Assigned | | |
| Attorney Docket Number | Q76579 | | |

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| Examiner Initials* | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published | Translation |
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| Examiner Signature | Date Considered |
|--------------------|-----------------|
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English